



Response of iLGAD sensors to high intensity photons absorbed within and close to the gain layer

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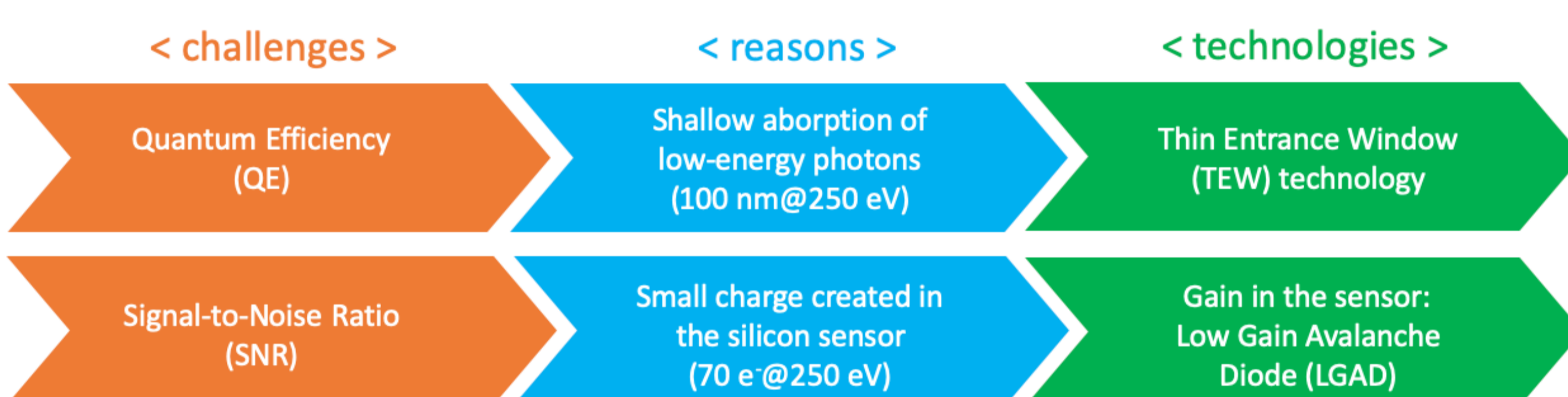
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Introduction

Hybrid X-ray detectors are state-of-the-art for imaging experiments using hard X-rays at synchrotrons and free-electron lasers (FELs), thanks to their high frame rate, large dynamic range and large detection area. However, they have not been used in soft X-ray energy range due to low **Quantum Efficiency (QE)** and **Signal-to-Noise Ratio (SNR)** [1].

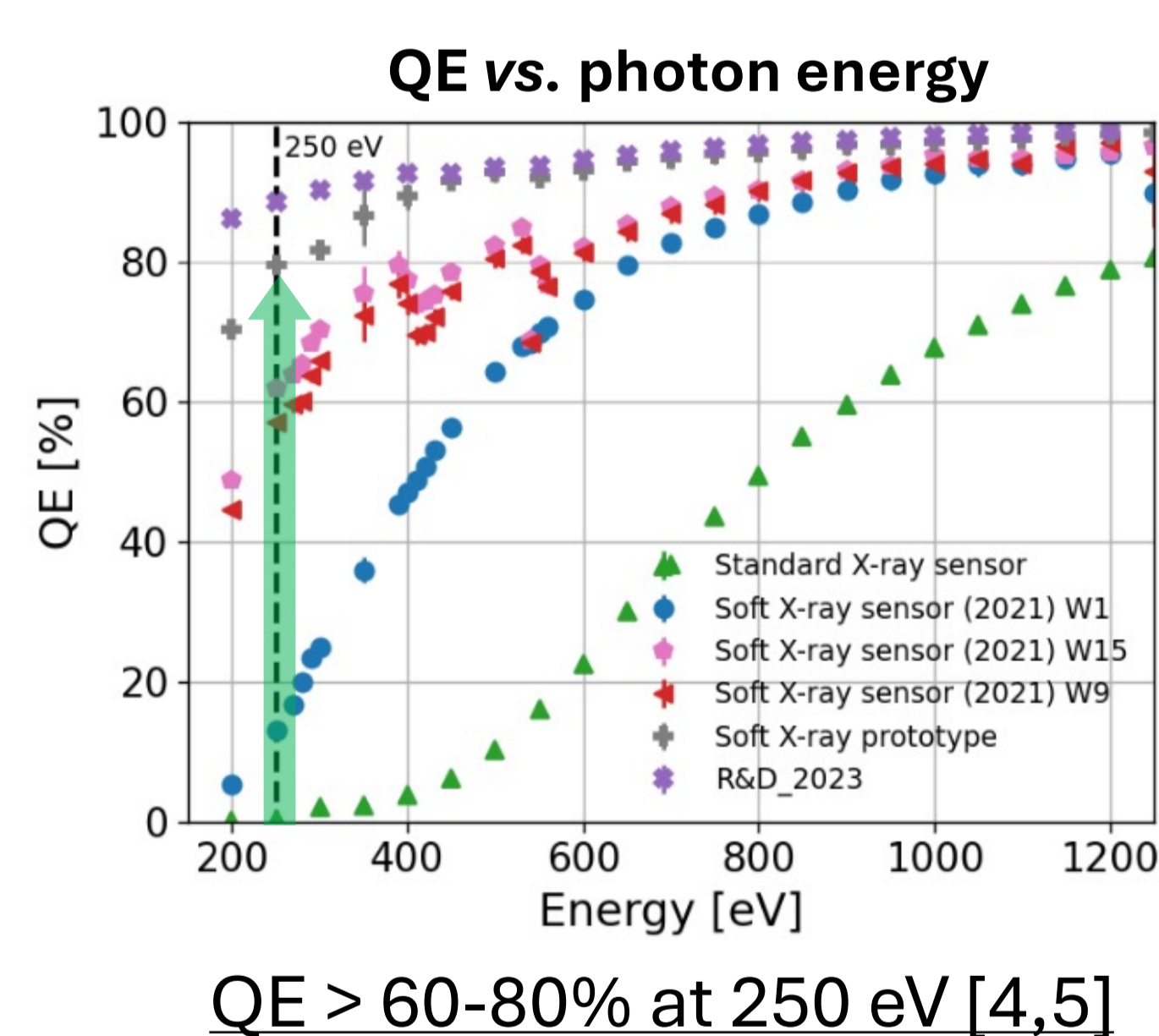
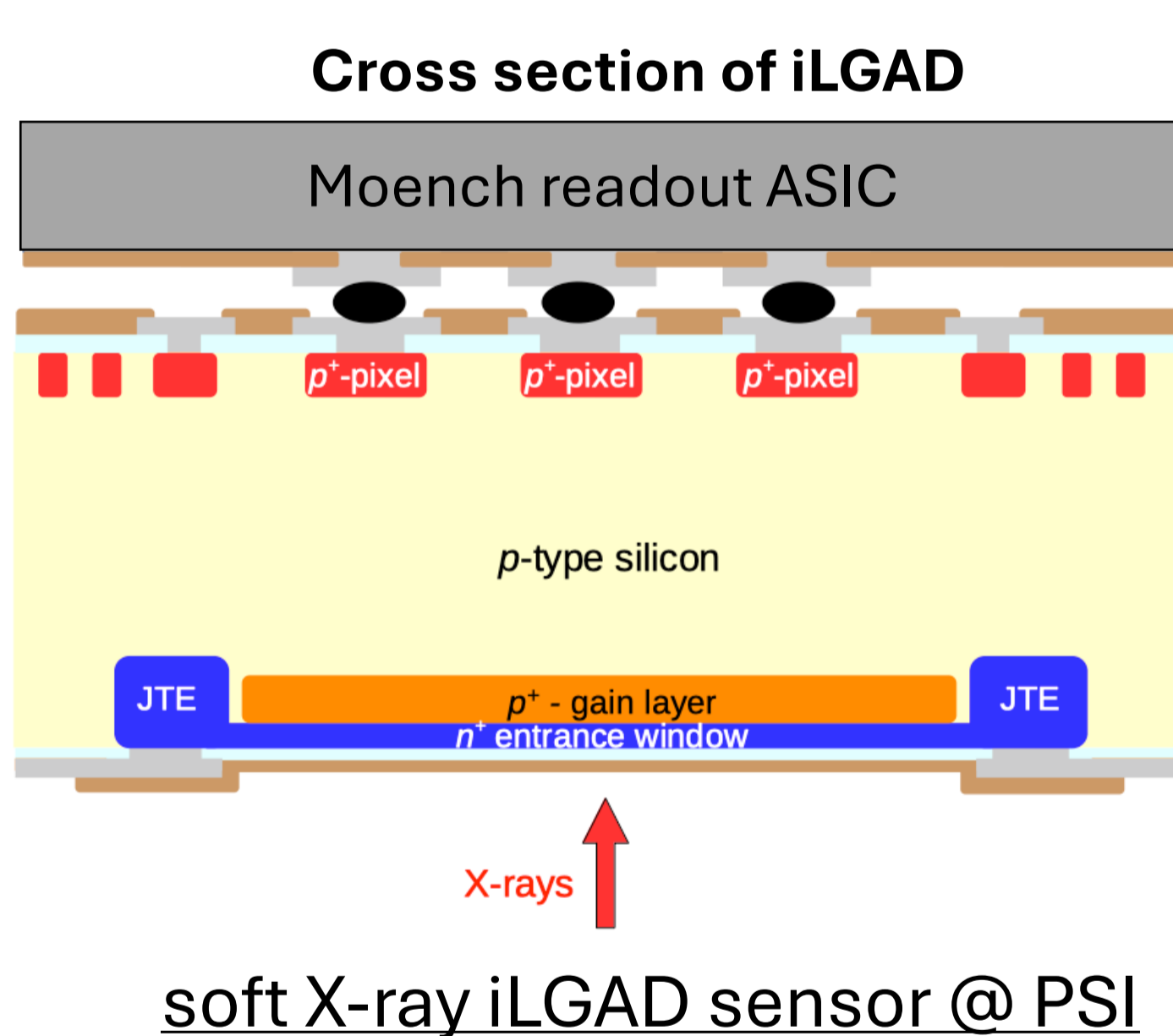
To overcome these challenges, two technologies are being developed in collaboration with FBK: a **Thin Entrance Window (TEW)** technology to increase the QE and **Low Gain Avalanche Diode (LGAD)** technology, tailored for photon science, to improve the SNR [2].



Rewind: Recent developments at PSI

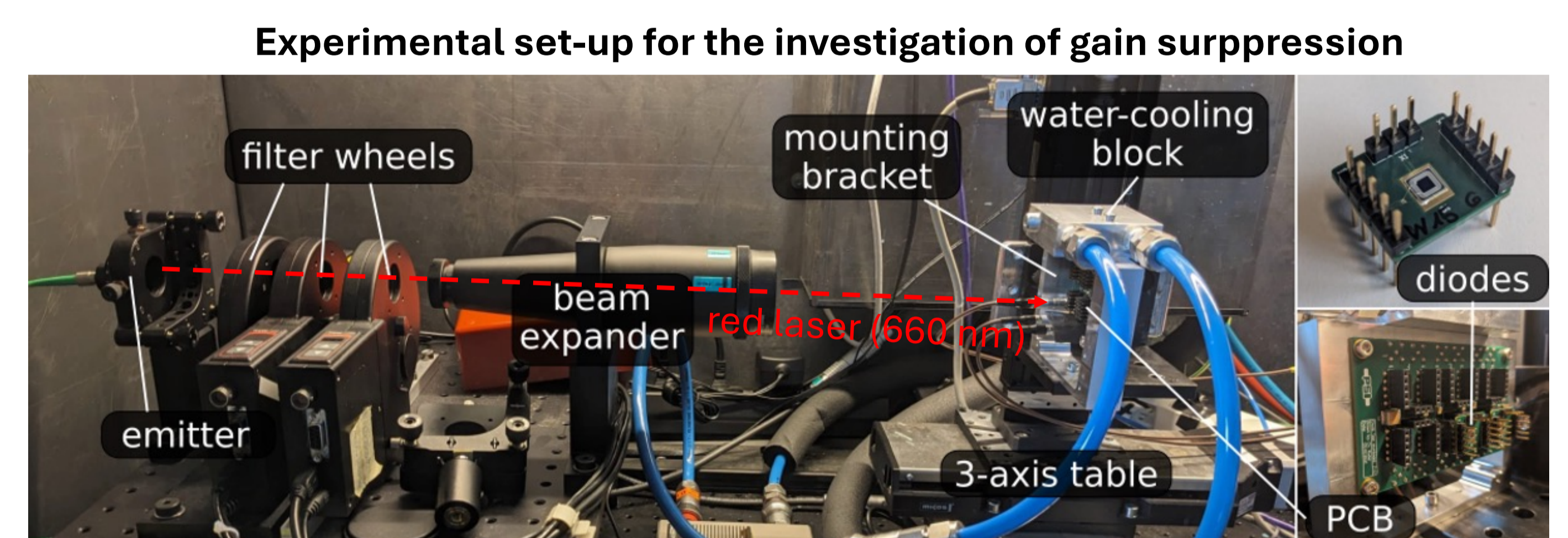
The inverse LGAD (iLGAD) sensors with a TEW optimized for soft X-rays:

- 100% fill factor → interpolation possible for high spatial resolution [3]
- Gain depends on photon absorption depth → lower gain for < 400 eV



Response to high intensity photons

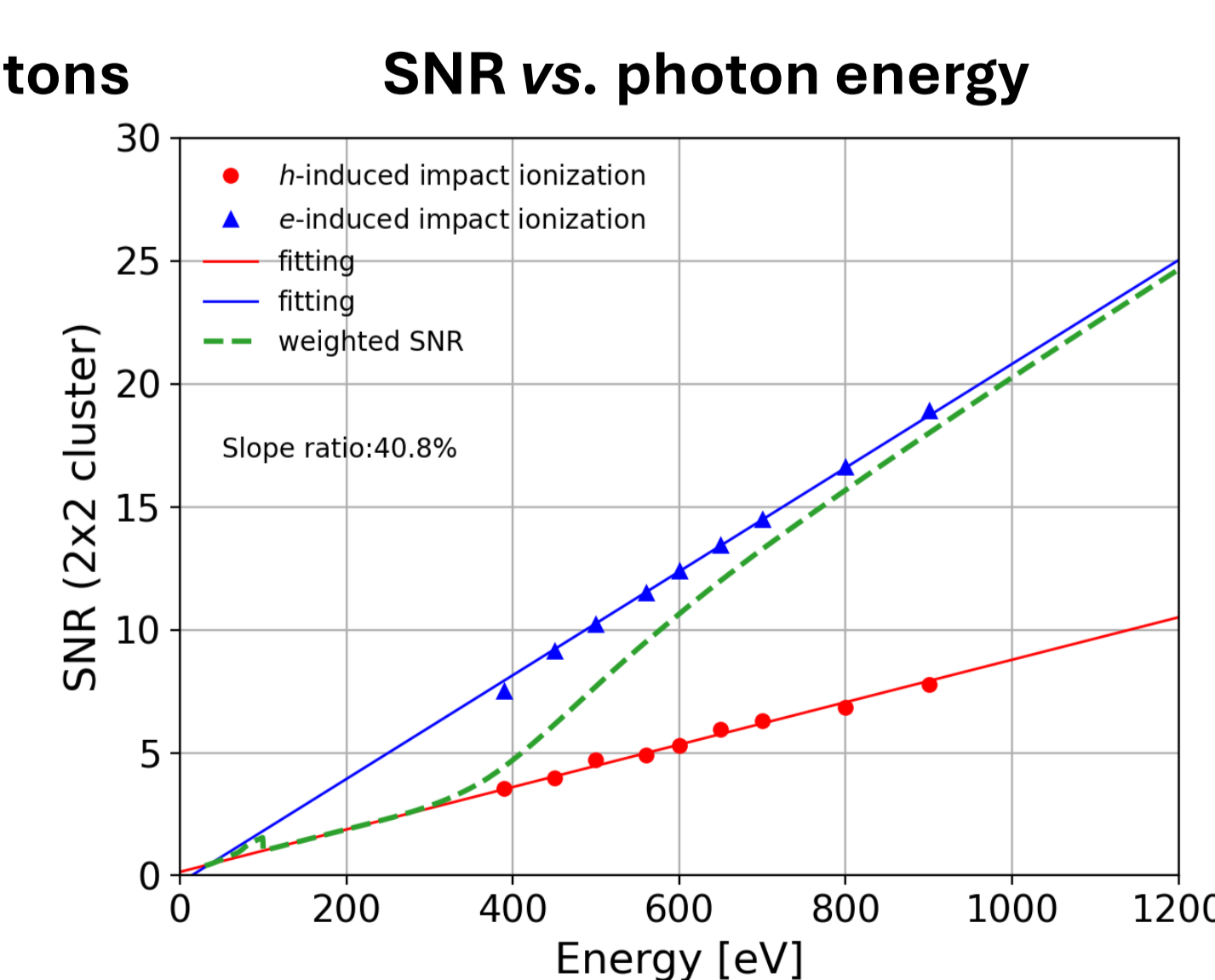
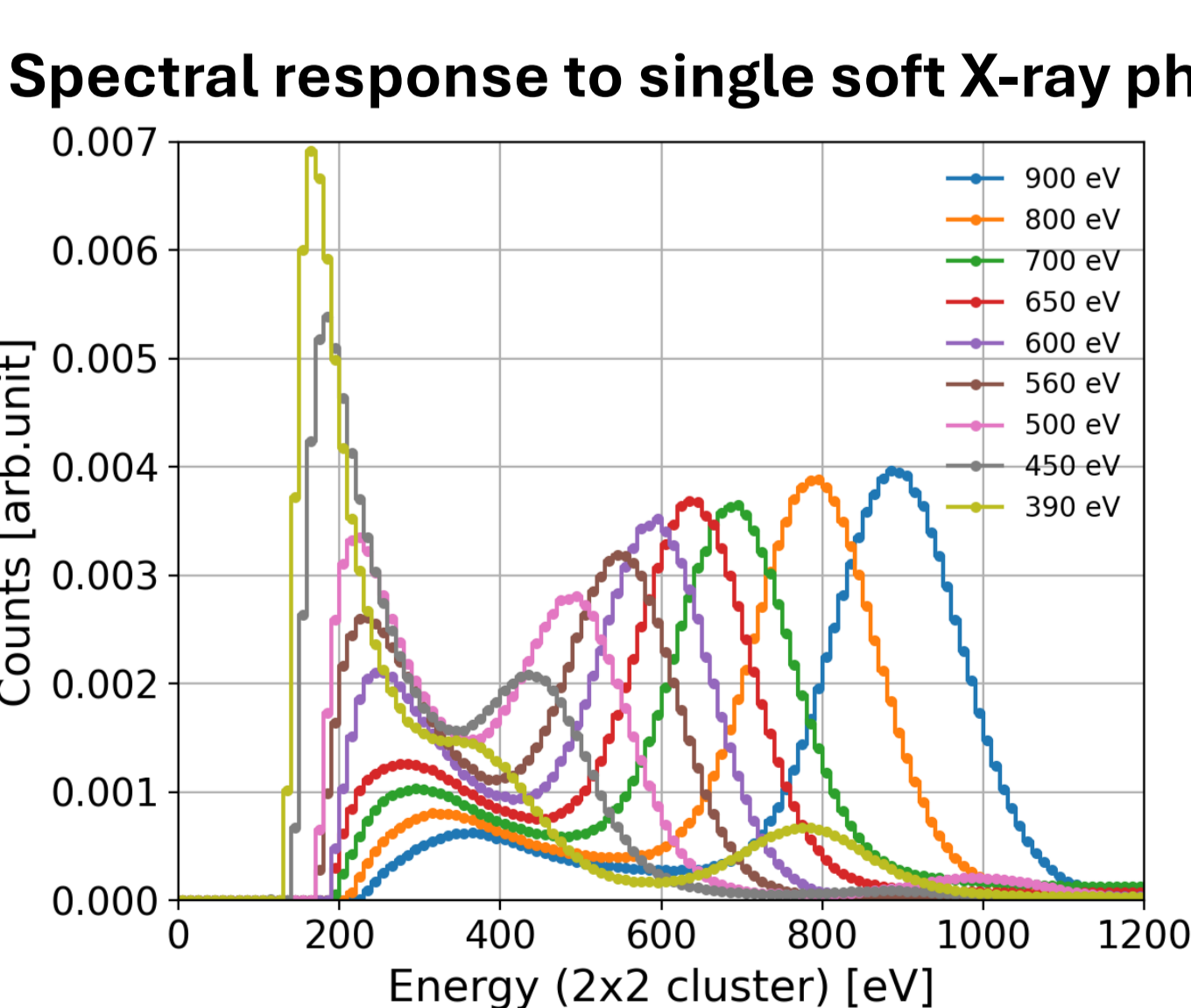
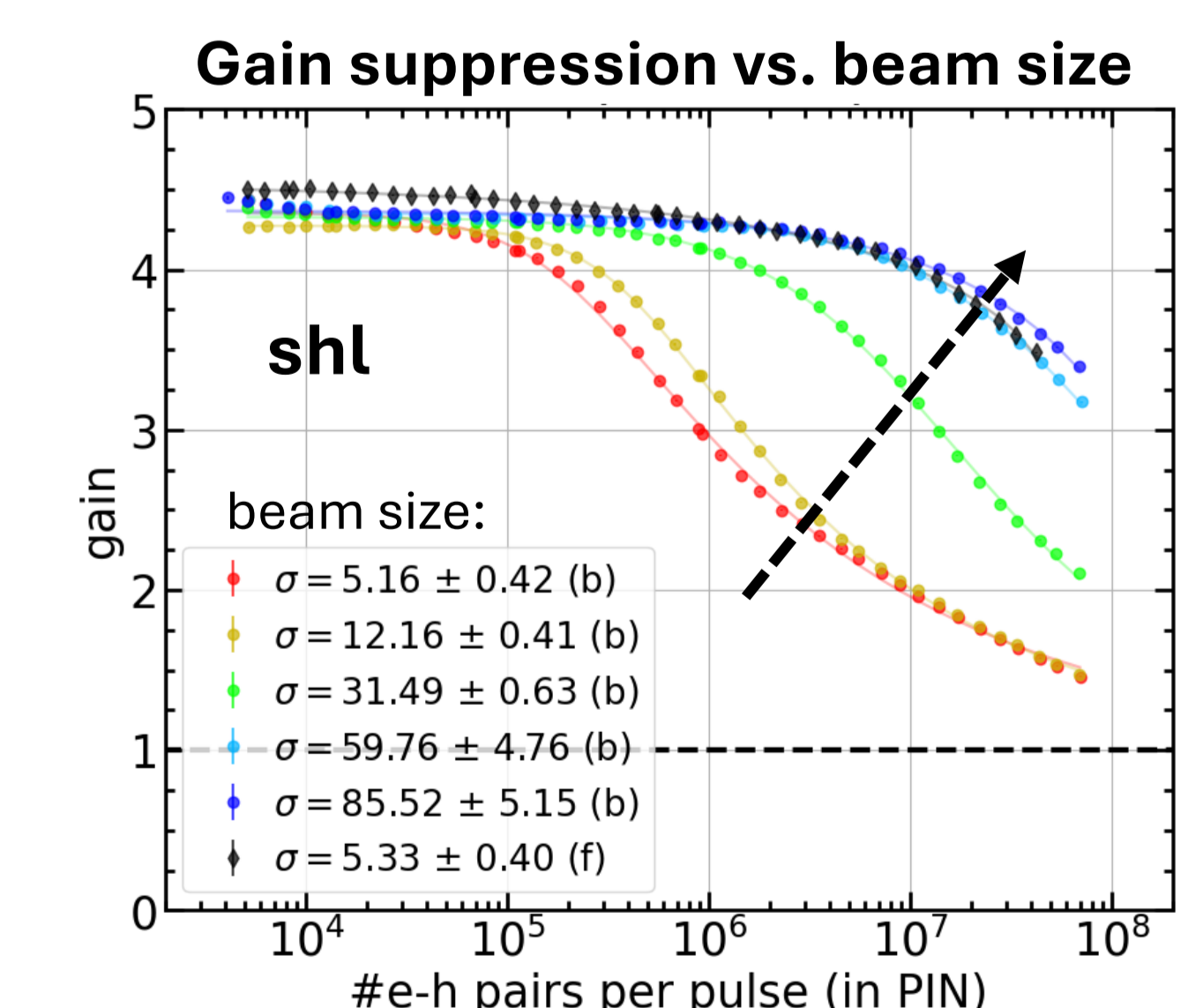
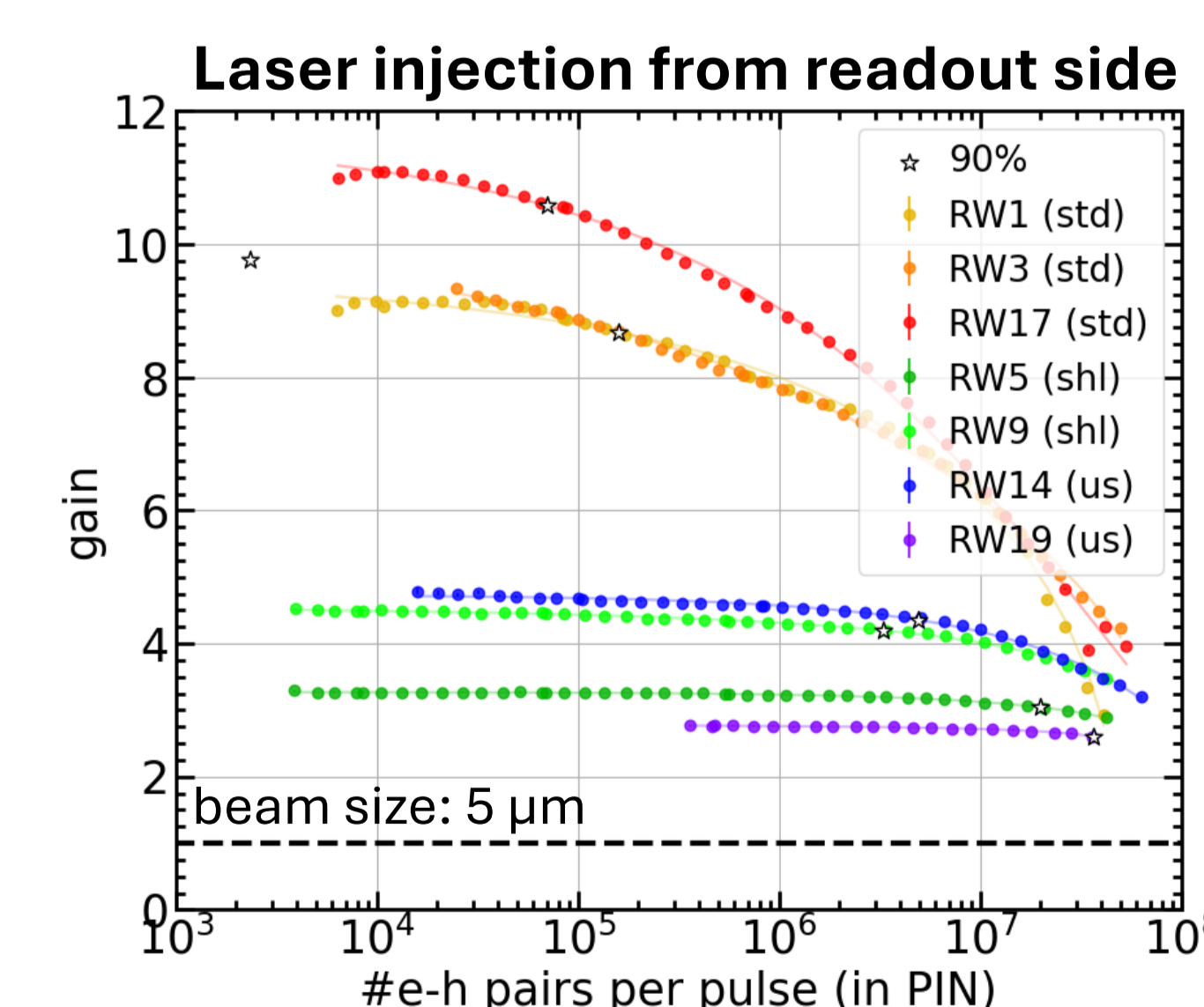
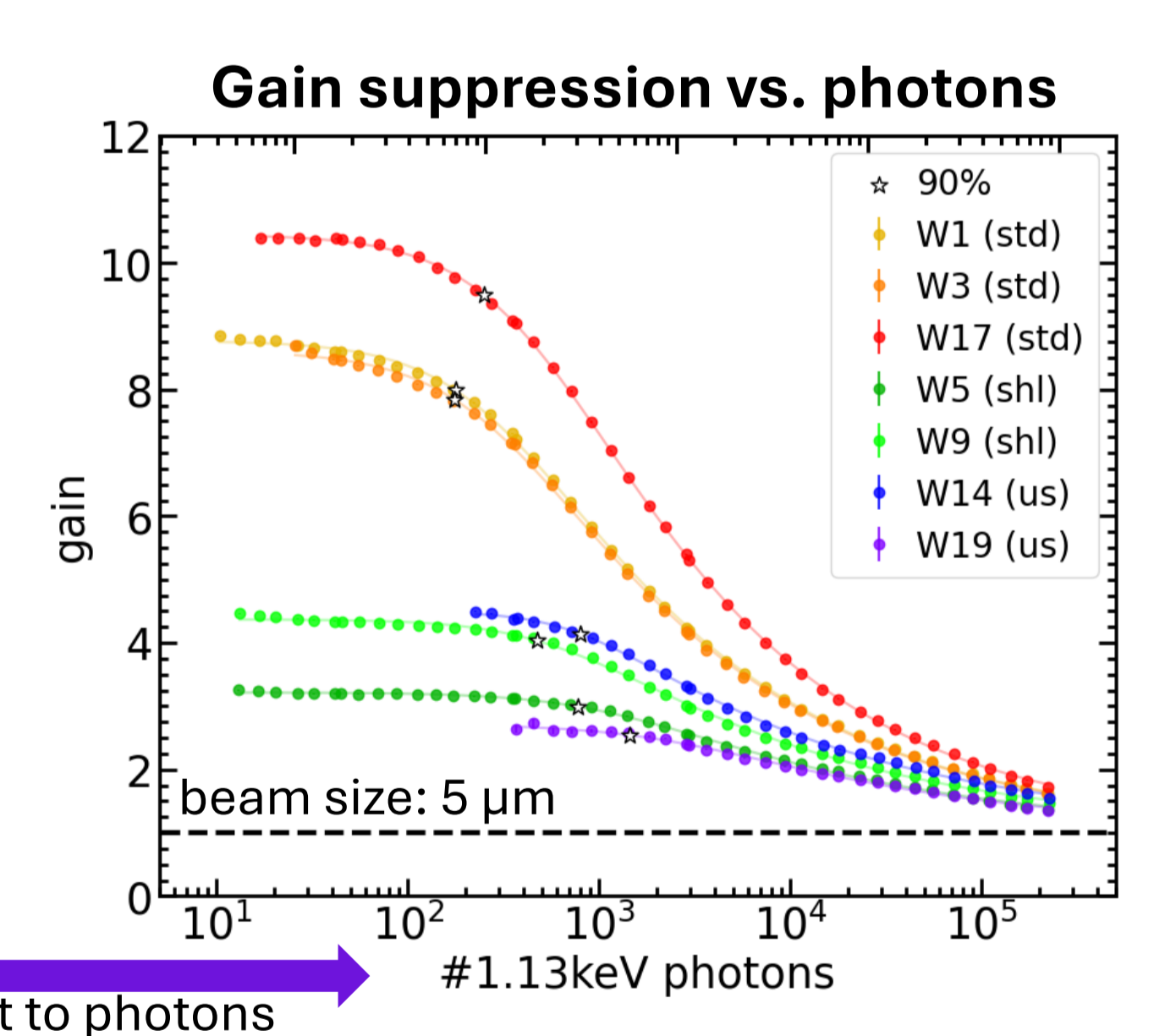
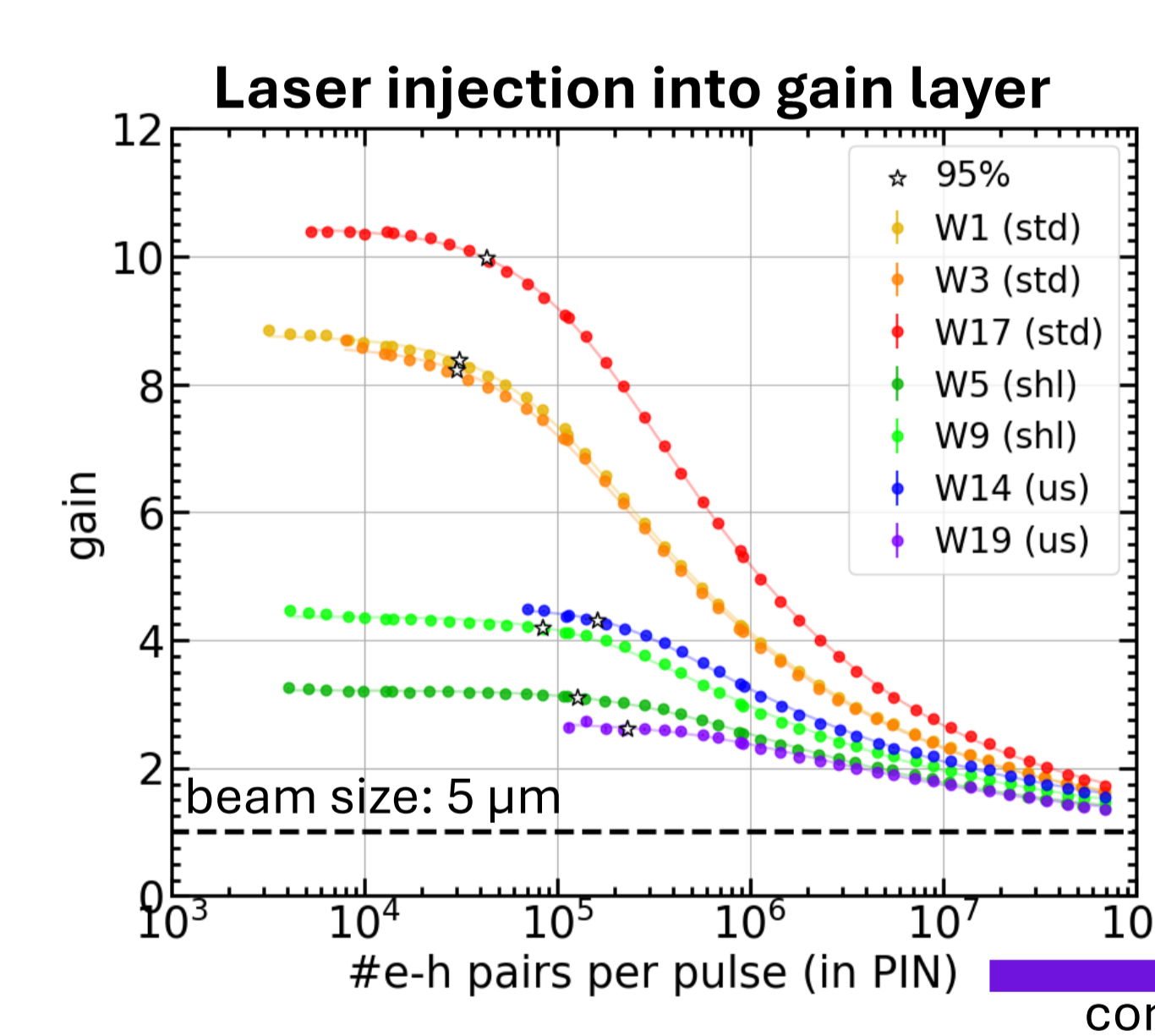
X-ray photons (total energy up to 10^5 keV) arrive on the silicon sensor simultaneously from a single XFEL pulse. A large number of charge carriers are created within and close to the gain layer of the iLGAD sensor, which reduces the electric field in the gain layer and thus causes gain suppression.



Experimental set-up and measurements:

- Pulsed red laser (660 nm) → absorption depth in silicon: $3.88 \mu\text{m}$
- Laser intensity was varied using filters
- Photocurrent of iLGAD sensors with 3 different gain designs (standard - std, shallow - shl and ultrashallow - us) and diodes were measured → gain determined as function of $e-h$ pairs produced by each pulse

Results and conclusions



Single-photon detection down to 390 eV [6] SNR greater than 5 for $E > 390$ eV

References

- [1] Andrae et al., *JSR* **26**, 1226 (2019).
- [2] Zhang et al., *JINST* **17**, C11011 (2022).
- [3] Hinger et al., *Front. Phys.* **12**, 1352134 (2024).
- [4] Carulla et al., *JINST* **18**, C01073 (2023).
- [5] Carulla et al., *Sensors* **24**(3) (2024).
- [6] Liguori et al., *JINST* **18**, P12006 (2023).
- [7] Frank, ETHZ semester thesis (unpublished)

Gain suppression depends on [7]:

- Intensity (total number of $e-h$ pairs produced per pulse)
- Beam size → initial charge distribution
- Gain layer design → shallow/ultrashallow gain layer is preferred
- Charge density when carriers reach the gain layer by drift/diffusion

Implications for photon science:

- Non-linear detector response at high X-rays intensity
- Calibration procedures need to be implemented for FEL applications